

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TW1-8520	Application Number NEW 10/717,316
	Applicant(s) Allan Rosencwaig et al.	
	Filing Date HEREWITH	Group Art Unit Unknown 2877

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
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							YES	NO
<i>[Signature]</i>	*AI	WO 95/00681	01/05/1995	PCT	C23G	1/00		
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<i>[Signature]</i>	*AN	K. Imen et al., "Laser-assisted micron scale particle removal," <i>App. Phys. Lett.</i> , Vol. 58, No. 2, 14 January 1991, pp. 203-205.
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Examiner <i>[Signature]</i>	Date Considered 23 July 2004
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	